

P3001A Investigation of Si etch reaction with F and O radicals using SF₆/O₂ plasma

M. Sekine, S. Amasaki, T. Takeuchi, K. Ishikawa, K. Takeda, H. Kondo, M. Hori
Nagoya University, Japan

P3002A Measurement of Br atom density in an inductively-coupled HBr plasma by appearance mass spectrometry

¹Y. Fujii, ¹T. Oike, ²D. Iino, ²K. Suzuki, ^{1,3}H. Toyoda
¹Nagoya University, Japan
²Corporate Manufacturing Engineering Center, Toshiba, Japan
³Nagoya University, Japan

P3003A Sequential exposure of N and H atoms for recovery of plasma-damaged GaN

¹Z. Liu, ¹S. Chen, ¹Y. Lu, ¹R. Kometani, ¹K. Ishikawa, ²H. Kano, ¹K. Takeda, ¹H. Kondo, ¹M. Sekine, ³T. Egawa, ¹H. Amano, ¹M. Hori
¹Nagoya University, Japan
²NU Eco Engineering Co., Ltd., Japan
³Nagoya Institute of Technology, Japan

P3004A Real-time variation of sputtering yield of Ar ion for ArF photoresist during Ar plasma exposure

¹T. Takeuchi, ²C. Corbella, ²S. Grosse-Kreul, ²A. Keudell, ¹K. Ishikawa, ¹H. Kondo, ¹K. Takeda, ¹M. Sekine, ¹M. Hori
¹Nagoya University, Japan
²Ruhr-University at Bochum, Germany

P3005A The change in surface morphology of Si at elevated temperature during the plasmaless Si etching with NO/F₂ gas mixture

S. Tajima, T. Hayashi, K. Ishikawa, M. Sekine, M. Hori
Nagoya University, Japan

P3006A Subsequent temporal change of gaseous H and N radical density in H₂/N₂ plasma after air exposure and its control

¹T. Suzuki, ^{1,2}K. Takeda, ¹K. Ishikawa, ¹H. Kondo, ^{1,2}M. Sekine, ^{1,2}M. Hori
¹Nagoya University, Japan
²JST-CREST, Japan

P3007A Gas-phase reaction model of Ar-diluted CHxFy plasmas

Y. Kondo, Y. Miyawaki, K. Takeda, H. Kondo, K. Ishikawa, T. Hayashi, M. Sekine, M. Hori
Nagoya University, Japan

P3008A **Mechanism for degradation of porous SiOCH low-k films by O₂ plasma**

K. Asano, K. Ishikawa, M. Sekine, K. Takeda, H. Kondo, M. Hori
Nagoya University, Japan

P3009A **Defects introduced in germanium substrate by reactive ion etching**

K. Ndari, W. Takeuchi, M. Sakashita, N. Taoka, O. Nakatsuka, S. Zaima
Nagoya University, Japan

P3010A **Investigation of sticking coefficient of hydrogen radical on ArF 193 nm chemically amplified resist**

^{1,2}A. Malinowski, ¹T. Takeuchi, ¹T. Suzuki, ¹M. Hori, ¹M. Sekine, ¹H. Kondo, ¹K. Ishikawa, ²L. Lukasiak, ²A. Jakubowski
¹Nagoya University, Japan
²Warsaw University of Technology, Poland

P3011A **Excitation dissociations of c-C₃F₈ and c-C₃HF₇ etching gases**

T. Hayashi, K. Ishikawa, M. Sekine, M. Hori
Nagoya University, Japan

P3012A **Low-damage, high-accuracy plasma etching of Ga-compound semiconductors**

J. Cao, R. Kometani, J. Park, K. Ishikawa, K. Takeda, H. Kondo, M. Sekine, M. Hori
Nagoya University, Japan

P3013A **Numerical analysis of damage formation in vertical-walls gate etching processes**

K. Mizotani, M. Isobe, S. Hamaguchi
Osaka University, Japan

P3014A **FIOG-purpose ultra-thin metal precision layered composite material technology for the manufacture of Fine Clad materials**

S. Lim, B. Jin, K. Heo, J. Ho, H. Kwon
Korea Institute of Industrial Technology, Korea

P3015A **H₂ plasma cleaning of poly-Si film by using pulse power supply**

¹K. Hashimoto, ¹K. Tada, ¹S. Yasui, ²T. Manabe, ²K. Koike
¹Nagoya Institute of Technology, Japan
²Iwatani Corp, Japan

P3016A **Model based analysis of etching mechanism of HfO₂ and SiO₂ films in an inductively coupled BCl₃/Cl₂/O₂ plasma for dielectric mask**

¹J. Son, ²A. Efremov, ¹S. Kang, ¹Y. Ham, ¹H. Jang, ¹K. Kwon

¹Korea University, Korea

²State University of Chemistry & Technology, Russia

P3017A **Dependence of exposure distance on inactivation of *P. digitatum* spores using low-temperature atmospheric pressure radical source**

¹M. Ito, ¹H. Hashizume, ¹T. Ohta, ²F. Jia, ²K. Takeda, ²K. Ishikawa, ²M. Hori

¹Meijo University, Japan

²Nagoya University, Japan

P3018A **SAKAKITA plasma treatment as a minimum invasive method for hemostasis**

^{1,2}Y. Ikehara, ²H. Sakakita, ¹S. Ikehara, ³H. Nakanishi

¹National Institute of Advanced Industrial Science and Technology (AIST), Japan

²National Institute of Advanced Industrial Science and Technology (AIST), Japan

³Aichi Cancer Center Research Institute, Japan

P3019A **Real-time *in-situ* monitoring of fluorescent images of *P. digitatum* spores during oxygen radical treatment using confocal laser microscopy**

¹H. Hashizume, ¹T. Towatari, ¹H. Ohashi, ¹T. Ohta, ²M. Hori, ¹M. Ito

¹Meijo University, Japan

²Nagoya University, Japan

P3020A **Damages of biological components in bacteria and bacteriophages by plasma-exposure**

A. Mizuno, K. Takashima, H. Kurita, H. Yasuda

Toyohashi University of Technology, Japan

P3021A **Pulmonary diseases with inhalation of atmospheric pressure plasma flow**

^{1,2}T. Hirata, ^{1,2}C. Tsutsui, ^{1,2}A. Mori

¹Tokyo City University, Japan

²Tokyo City University, Japan

P3022A **Plasma-activated medium selectively killed glioblastoma brain tumor cells and induced apoptosis**

^{1,2}H. Tanaka, ²M. Mizuno, ¹K. Ishikawa, ³K. Nakamura, ³H. Kajiyama, ⁴H. Kano, ³F. Kikkawa, ¹M. Hori

¹Nagoya University, Japan

²Nagoya University, Japan

³Nagoya University, Japan

⁴NU Eco-Engineering Co., Ltd., Japan

P3023A **Gene transfer system using water mist plasma flow**

T. Kaneko, S. Sasaki, H. Konishi, M. Kanzaki
Tohoku University, Japan

P3024A **Possibility of plasma generation and sterilization in water using An Er:YAG laser**

¹T. Shirafuji, ²K. Takahashi, ³H. Kambayashi, ⁴T. Goto
¹Osaka City University, Japan
²Kanazawa University, Japan
³Keyaki Doori Dental Clinic, Japan
⁴White Net, Japan

P3025A **Electron spin resonance study of plasma-biological surface interaction for food hygiene**

K. Ishikawa, ¹H. Mizuno, ¹H. Tanaka, ²H. Hashizume, ²T. Ohta, ²M. Ito, ¹K. Takeda, ¹H. Kondo, ¹M. Sekine, ¹M. Hori
¹Nagoya University, Japan
²Meijo University, Japan

P3026A **Teeth whitening with pulsed microwave power atmospheric pressure plasma**

S. Kwon, H. Lee, S. Kang, H. Lee, J. Lee
Pohang University of Science and Technology, Korea

P3027A **Plasma-biological surface interaction investigated by electron spin resonance**

¹H. Mizuno, ¹K. Ishikawa, ¹H. Tanaka, ²H. Hashizume, ²T. Ohta, ²M. Ito, ¹K. Takeda, ¹H. Kondo, ¹M. Sekine, ¹M. Hori
¹Nagoya University, Japan
²Meijo University, Japan

P3028A **Plasma-biomaterials interaction analysis as a basis of fundamental processes in plasma medicine**

Y. Setsuhara, ¹K. Takenaka, ²M. Shiratani, ³M. Sekine, ³M. Hori
¹Osaka University, Japan
²Kyushu University, Japan
³Nagoya University, Japan

P3029A **Effect of pulsed discharge plasma irradiation on the elongation of alanine and alanylalanine under ambient aqueous and hydrothermal conditions**

¹M. Sasaki, ¹A. Nagira, ¹K. Nagafuchi, ¹A. Quitain, ²Wahyudiono, ²M. Goto, ³K. Kawamura
¹Kumamoto University, Japan
²Nagoya University, Japan
³Hiroshima Shudo University, Japan

P3030A **Raman spectroscopy of penicillium digitatum spores treated by atmospheric-pressure oxygen-radical source**

¹H. Kato, ¹H. Hashizume, ¹T. Ohta, ¹M. Hiramatsu, ¹M. Ito, ²M. Hori

¹Meijo University, Japan

²Nagoya University, Japan

P3031A **Quantitative evaluation of intensity of radical reaction by plasma exposure using the DNA combing method**

H. Kurita, T. Nakajima, H. Yasuda, K. Takashima, A. Mizuno

Toyohashi University of Technology, Japan

P3032A **Assessment of mutaton probability in yeast by plasma exposure using the stress reporting system**

H. Yasuda, T. Eki, H. Kurita, K. Takashima, A. Mizuno

Toyohashi University of Technology, Japan

P3033A **Estimation of incident radical and ion fluxes onto electrode in atmospheric pressure radio-frequency capacitive plasmas in helium with impurities**

A. Oda, T. Imazeki, N. Saitoh, J. Sakashita

Chiba Institute of Technology, Japan

P3034A **Plasma-mediated modulation of element distribution in skin and skin cancer**

¹I. Yajima, ¹M. Iida, ¹K. Nakagawa, ²H. Kondo, ¹M. Kumasaki, ²K. Takeda, ²M. Hori, ³H. Kano, ¹M. Kato

¹Chubu University, Japan

²Nagoya University, Japan

³NU Eco Engineering Co., Ltd., Japan

P3035A **Nonequilibrium atmospheric pressure plasma selectively killed ovarian cancer cells and induced apoptosis.**

^{1,2}H. Tanaka, ¹S. Iseki, ³K. Nakamura, ³M. Hayashi, ¹H. Kondo, ³H. Kajiyama, ⁴H. Kano, ³F. Kikkawa, ¹M. Hori

¹Nagoya University, Japan

²Nagoya University, Japan

³Nagoya University, Japan

⁴NU Eco-Engineering Co., Ltd., Japan

P3036A **Changes in the components of enveloped and non-enveloped viruses after treatment with N₂ gas plasma**

¹A. Sakudo, ²N. Shimizu, ²Y. Imanishi

¹University of the Ryukyus, Japan

²Ngk Insulators, Ltd., Japan

P3037A **Unravelment of complex plasma chemistry in atmospheric-pressure He-O₂ plasmas with humid air impurities**

¹T. Murakami, ²K. Niemi, ²T. Gans, ²D. O'Connell, ³W. Graham

¹Tokyo Institute of Technology, Japan

²University of York, UK

³Queen's University Belfast, UK

P3038A **Fabrication of polyacrylate brushes on plasma-irradiated polystyrene substrate for cell culture applications**

¹Y. Sasai, ¹A. Komatsu, ¹S. Kondo, ²Y. Yamauchi, ³M. Kuzuya

¹Gifu Pharmaceutical University, Japan

²Matsuyama University, Japan

³Chubu Gakuin University, Japan

P3039A **Electrochemical characteristics of TiN/ZrN multilayers on the Ti-35Ta-xHf alloy using magnetron sputtering**

B. Moon, H. Choe

Chosun University, Korea

P3040A **Measuremant of singlet oxygen molecule densities in the inactivation process of *P. digitatum* spores using low-temperature atmospheric pressure radical source**

¹H. Hashizume, ¹T. Ohta, ¹M. Ito, ²F. Jia, ²K. Takeda, ²K. Ishikawa, ²M. Hori

¹Meijo University, Japan

²Nagoya University, Japan

P3041A **Atmospheric-pressure non-equilibrium hybrid plasma for surface sterilization**

A. Yonesu, ¹N. Yoneyama, ¹T. Sagara, ²N. Hayashi

¹University of the Ryukyus, Japan

²Kyushu University, Japan

P3042A **Growth enhancement of plants using atmospheric pressure dielectric barrier discharge plasmas**

T. Sarinont, ¹S. Kitazaki, ¹G. Uchida, ¹K. Koga, ¹M. Shiratani, ²N. Hayashi

¹Kyushu University, Japan

²Kyushu University, Japan

P3043A **Antioxidative activity of plant and regulation of plant growth induced by oxygen radicals**

N. Hayashi, ²S. Kitazaki, ²K. Koga, ²M. Shiratani

¹Kyushu University, Japan

²Kyushu University, Japan

P3044A **Sterilization device using air plasma under reduced-pressure environment**

¹D. Yoshino, ²K. Nakamuraya, ¹T. Nakajima, ¹T. Sato

¹Tohoku University, Japan

²Tohoku University, Japan

P3045A **Radio frequency capacitive plasma surface treatment of titanium implant for initial adhesion and proliferation of preosteoblast cell**

¹B. Kim, ¹S. Myung, ¹Y. Hwang, ¹Y. Hwang, ²S. Jung

¹Chosun University, Korea

²Sunchon National University, Korea

P3046A **Plasma sputtered hydroxyapatite(HA)/TiN film coating on the Ti-29Nb-5Zr alloy for biocompatibility**

H. Choe, E. Kim

Chosun University, Korea

P3047A **Fundamental study of dissolved OH radicals in the liquid produced by atmospheric pressure plasma jet**

¹T. Yamahara, ²T. Ishijima, ³M. Imamura, ^{2,4}K. Ninomiya, ^{2,4}K. Takahashi, ^{1,2}Y. Tanaka, ^{1,2}Y. Uesugi

¹Kanazawa University, Japan

²Kanazawa University, Japan

³Kanazawa University, Japan

⁴Kanazawa University, Japan

P3048A **Inhibition of *in vitro* prion replication by N₂ gas plasma**

¹A. Sakudo, ²N. Shimizu, ²Y. Imanishi

¹University of The Ryukyus, Japan

²Ngk Insulators, Ltd., Japan

P3049A **Immobilization of hyaluronic acid on amine plasma polymerized polycaprolactone scaffolds for MC3T3-E1 cell attachment and proliferation**

¹D. Choi, ²S. Yang, ³S. Jung, ⁴B. Kim

¹Chosun University, Korea

²Chosun University, Korea

³Sunchon National University, Korea

⁴Chosun University, Korea

P3050A **Plasma surface modification for immobilization of bone morphogenic Protein-2 on polycaprolactone scaffolds**

S. Myung, Y. Hwang, Y. Hwang, Y. Ko, B. Kim

Chosun University, Korea

P3051A **Effect of biological solution on generation of radical species induced by nonequilibrium atmospheric pressure plasma**

¹J. Jolibois, ²K. Takeda, ²H. Tanaka, ¹K. Ishikawa, ^{1,2}M. Hori

¹Nagoya University, Japan

²Nagoya University, Japan

P3052A **Utilization of the solution plasma process for the production of low molecular weight alginate with narrow molecular weight distribution**

¹A. Watthanaphanit, ^{1,2}N. Saito

¹Nagoya University, Japan

²Nagoya University, Japan

P3053A **Effect of plasma treatment on BCP scaffolds for improving cellular activity**

Withdrawn

^{1,2}Y. Choi, ²D. Song, ³J. Lee, ³J. Han, ^{1,2}K. Kim, ^{1,2}K. Kim

¹Department and Research Institute of Dental Biomaterials and Bioengineering, Korea

²Yonsei University, Korea

³Sungkyunkwan University, Korea

P3054A **Effect of nonthermal plasma on tooth surface**

¹H. Choi, ¹K. Kim, ¹K. Kim, ²E. Choi

¹Yonsei University College of Dentistry, Korea

²Kwangwoon University, Korea

P3055B **Luminescence properties of Eu-doped GaN grown by selective-area organometallic vapor phase epitaxy**

¹R. Hasegawa, ¹R. Wakamatsu, ¹A. Koizumi, ²H. Ofuchi, ³M. Ichimiya, ¹D. Lee, ¹Y. Terai, ²T. Honma, ³M. Ashida, ¹Y. Fujiwara

¹Osaka University, Japan

²Japan Synchrotron Radiation Reserch Institute/ SPring-8, Japan

³Osaka University, Japan

P3056B **TEM analyses of GaN grown with AlInN intermediate layer on Si substrate**

¹S. Ito, ¹T. Nakagita, ¹H. Iwata, ¹N. Sawaki, ²M. Irie, ²Y. Honda, ²M. Yamaguchi, ²H. Amano

¹Aichi Institute of Technology, Japan

²Nagoya University, Japan

P3057B **Comparison of growth behavior in thick InGaN on (0001̄) and (0001) GaN/Sapphire by metalorganic vapor phase epitaxy**

^{1,2}T. Tanikawa, ¹K. Shojiki, ¹J. Choi, ^{1,2}R. Katayama, ^{1,2}T. Matsuoka

¹Tohoku University, Japan

²CREST, Japan Science and Technology Agency, Japan

P3058B **GaN growth on off-angle trench patterned GaN/sapphire templates by MOVPE**

Z. Cai, H. Miyake, K. Hiramatsu

Mie University, Japan

P3059B **Si doped AlN growth on trench patterned template by MOVPE**

G. Nishio, M. Narukawa, H. Miyake, K. Hiramatsu

Mie University, Japan

P3060B **Selective-area growth of GaN on nonpolar substrates**

¹S. Okada, ¹D. Jinno, ¹H. Miyake, ¹K. Hiramatsu, ²Y. Enatsu, ³S. Nagao

¹Mie University, Japan

²Mitsubishi Chemical Corporation, Japan

³Mitsubishi Chemical Group Science and Technology Research Center, Inc., Japan

P3061B **AlN/Al₂O₃ formed by Al₂O₃ substrate nitridation and GaN single crystal growth on AlN/Al₂O₃ substrate**

Withdrawn

¹T. Ozawa, ¹Y. Katsumata, ¹M. Dohi, ²Y. Hayakawa

¹Shizuoka Institute of Science and Technology, Japan

²Shizuoka University, Japan

P3062B **Growth and characterization of InGaN GaN multi-quantum well on regular nanoporous template**

C. Miao, Y. Honda, M. Yamaguchi, H. Amano

Nagoya University, Japan

P3063B **Influence of substrate temperature on In_xGa_{1-x}N films deposited by reactive RF-Sputtering**

²T. Suzuki, ¹S. Hibino, ¹R. Katayama, ¹Y. Kato, ¹F. Ohashi, ²T. Itoh, ²S. Nonomura

¹Gifu University, Japan

²Gifu University, Japan

P3064B **Characteristics of nonpolar *a*-plane GaN grown on *r*-plane sapphire substrate using two microscale SiO₂ masks**

¹J. Son, ¹Y. Honda, ¹M. Yamaguchi, ¹H. Amano, ²K. Baik, ³Y. Seo, ³S. Hwang

¹Nagoya University, Japan

²Hongik University, Korea

³Korea Electronics Technology Institute, Korea

P3065B **Characterization of electron traps in MOCVD p-GaN by minority carrier transient spectroscopy**

¹U. Honda, ¹T. Matsumura, ¹H. Naito, ¹Y. Tokuda, ²K. Shiojima

¹Aichi Institute of Technology, Japan

²Fukui University, Japan

P3066B **Selective growth of InGaN/GaN MQW on the apex of GaN pyramids**

J. Lee, Y. Yu, W. Yun, H. Ahn, M. Yang

Korea Maritime University, Korea

P3067B **Growth of GaN on metallic compound graphite substrate using HVPE**

¹J. Kim, ¹G. Lee, ¹S. Jung, ¹S. Bae, ¹M. Park, ¹M. Shin, ¹S. Yi, ¹M. Yang, ¹H. Ahn, ²Y. Yu, ²S. Kim, ³H. Lee, ⁵H. Kang, ⁶N. Sawaki

¹Korea Maritime University, Korea

²Pukyong National University, Korea

³Andong National University, Korea

⁴L&L. Co., Ltd., Korea

⁵CSsol. Co., Ltd., Korea

⁶AIT, Japan

P3068B **Improvement in the optical properties of a-plane InGaN/GaN MQW-based light emitting diodes using indium predeposition**

¹S. Yeon, ¹T. Son, ¹Y. Kim, ^{1,2}J. Park

¹Hanyang University, Korea

²Hanyang University, Korea

P3069B **In-situ observation of emission peak transition from GaN to Al_{0.34}Ga_{0.66}N by introducing in-situ cathode luminescence in plasma-assisted molecular beam epitaxy using high-density nitrogen radical source**

¹Y. Kawai, ^{1,2}Y. Honda, ^{1,2}M. Yamaguchi, ^{1,2}H. Amano, ¹H. Kondo, ³M. Hiramatsu, ⁴H. Kano, ⁵K. Yamakawa, ⁵S. Den, ^{1,6}M. Hori

¹Nagoya University, Japan

²Nagoya University, Japan

³Meijo University, Japan

⁴NU Eco-Engineering Co., Ltd., Japan

⁵Katagiri Engineering Co., Ltd., Japan

⁶Nagoya University, Japan

P3070B **Activity modulation MEE growth of group III nitrides on Si(111) using PA-MBE**

^{1,2}T. Ohachi, ²Y. Sato, ²S. Yoshikado, ²M. Wada, ³O. Ariyada

¹Doshisha University, Japan

²Doshisha University, Japan

³ARIOS Inc., Japan

P3071B **Molecular dynamics simulation of molecular beam epitaxy growth of GaN with gallium layers on GaN substrate**

H. Hayashi, T. Miki, T. Kawamura, Y. Suzuki
Mie University, Japan

P3072B **FTIR analyses of carbon doped (1-101) GaN grown on a patterned Si substrate**

¹K. Hagiwara, ¹N. Sawaki, ²K. Yamashita, ²T. Tanikawa, ²Y. Honda, ²M. Yamaguchi, ²H. Amano
¹Aichi Institute of Technology, Japan
²Nagoya University, Japan

P3073B **Defect structure in a (1-101) GaN grown on a patterned (001) Si substrate**

¹T. Nakagita, ¹S. Ito, ¹H. Iwata, ¹N. Sawaki, ²T. Tanikawa, ²Y. Honda, ²M. Yamaguchi, ²H. Amano
¹Aichi Institute of Technology, Japan
²Nagoya University, Japan

P3074B **Influence of InAlN Spacer on Electrical Properties of AlGaN/GaN Heterostructure**

A. Watanabe, K. Mori, T. Ito, T. Egawa
Nagoya Institute of Technology, Japan

P3075B **Synthesis and enhanced optical property of Eu²⁺-doped GaN/SiO₂ nanocomposites**

B. Kang, M. Kim, D. Yoon
Sungkyunkwan University, Korea

P3076B **High-temperature ICTS study on ICP etching damages for p-GaN surfaces**

¹T. Aoki, ¹H. Wakayama, ²N. Kaneda, ²T. Mishima, ³K. Nomoto, ¹K. Shiojima
¹University of Fukui, Japan
²Hitachi Cable Ltd., Japan
³University of Notre Dame, USA

P3077B **Effect of UV irradiation on Ar-Plasma etching characteristics of GaN**

¹Y. Nakano, ¹K. Nakamura, ²M. Niibe, ³R. Kawakami, ¹N. Ito, ²T. Kotaka, ³K. Tominaga
¹Chubu University, Japan
²University of Hyogo, Japan
³University of Tokushima, Japan

P3078B **Deep level investigation of thick InGaN films**

¹Y. Nakano, ²M. Niibe, ³M. Lozac'H, ³L. Sang, ³M. Sumiya

¹Chubu University, Japan

²University of Hyogo, Japan

³National Institute for Materials Science, Japan

P3079B **The correlation between the morphology of threading dislocations and the origin of high-resistivity GaN**

Withdrawn

^{1,2}L. Lu, ^{1,2}S. Ma, ^{1,2}B. Xu

¹Taiyuan University of Technology, China

²Shanxi Research Center of Advanced Materials Science and Technology, China

P3080B **Characteristic analysis of hybrid photovoltaic devices with different surface structures of GaN**

¹D. Gwon, ¹M. Shin, ¹M. Kim, ¹G. Lee, ¹H. Ahn, ¹S. Yi, ²S. Yoon, ²C. Lee, ³D. Ha, ⁴N. Sawaki

¹Korea Maritime University, Korea

²Korea Research Institute of Chemical Technology, Korea

³Korea Research Institute of Standards and Science, Korea

⁴Aichi Institute of Technology, Japan

P3081B **Synthesis of hybrid heterojunction based on GaN nanostructures with optimized thickness of organic layer**

¹M. Shin, ¹M. Kim, ¹D. Gwon, ¹G. Lee, ¹H. Ahn, ¹S. Yi, ²D. Ha, ³N. Sawaki

¹Korea Maritime University, Korea

²Korea Research Institute of Standards and Science, Korea

³Aichi Institute of Technology, Japan

P3082B **Electrical properties of AlGaN/GaN MIS-HEMTs with Al₂O₃ deposited by ozone-based atomic layer deposition**

T. Kubo, Y. Iwata, T. Egawa

Nagoya Institute of Technology, Japan

P3083B **Fabrication of subwavelength grating with high aspect ratio on GaN LED**

Y. Takashima, R. Shimizu, Y. Naoi

The University of Tokushima, Japan

P3084B **InGaN-based solar cells with a tapered GaN structure**

Withdrawn

K. Chen, C. Lin, R. Jiang, C. Yang, W. Huang

National Chung Hsing University, Taiwan

P3085B **Site-selective characterization of Eu ion in gallium nitride**

R. Wakamatsu, D. Lee, A. Koizumi, Y. Fujiwara
Osaka University, Japan

P3086B **Characterization of SAG-GaN LED grown by HVPE method**

¹S. Jung, ¹G. Lee, ¹S. Bae, ¹H. Jeon, ¹M. Shin, ¹S. Yi, ¹M. Yang, ¹H. Ahn, ²Y. Yu, ³S. Kim, ⁴H. Kang, ⁵N. Sawaki
¹Korea Maritime University, Korea
²Pukyong National University, Korea
³Andong National University, Korea
⁴CSsol. Co., Ltd., Korea
⁵AIT, Japan

P3087B **A high efficiency InGaN solar cell with graded composition p-InGaN top layer**

T. Fujisawa, N. Sawaki
Aichi Institute of Technology, Japan

P3088B **Ohmic contact method of vertical GaN LED using pocket-type shadow mask**

¹G. Lee, ¹S. Jung, ¹S. Bae, ¹H. Jeon, ¹M. Shin, ¹S. Yi, ¹M. Yang, ¹H. Ahn, ²Y. Yu, ³S. Kim, ⁴H. Kang, ³N. Sawaki
¹Korea Maritime University, Korea
²Pukyong National University, Korea
³AIT, Japan

P3089B **Fabrication and characterization of single chip with Multi-GaN LED**

¹M. Park, ¹S. Bae, ¹G. Lee, ¹S. Jung, ¹J. Kim, ¹M. Shin, ¹S. Yi, ¹M. Yang, ¹H. Ahn, ²Y. Yu, ³S. Kim, ⁴H. Kang, ⁵N. Sawaki
¹Korea Maritime University, Korea
²Pukyong National University, Korea
³Andong National University, Korea
⁴CSsol. Co., Ltd, Korea
⁵AIT, Japan

P3090B **Comparison of optical and electrical properties of InGaN-based LED with different wavelength grown on Al₂O₃ with Co-doped ZnO film**

Withdrawn

¹Y. Fang, ^{1,2}R. Xuan, ¹C. Tsai, ³J. Huang
¹Industrial Technology Research Institute, Taiwan
²National Chiao Tung University, Taiwan
³National Cheng Kung University, Taiwan

P3091B **Large improved of n-GaN thickness by Mg-Si co-doped grown on Si (111) substrate**

Withdrawn

Y. Fang, C. Liao, R. Xuan, C. Lu

Industrial Technology Research Institute, Taiwan

P3092B **Countermeasures for EMI noises in power circuit using GaN switching device**

¹M. Saito, ²M. Iwasaki, ²T. Egawa

¹Shibaura Institute of Technology, Japan

²Nagoya Institute of Technology, Japan

P3093B **High rate growth of AlN and AlGaN on large diameter silicon substrate**

¹H. Tokunaga, ¹Y. Yamaoka, ¹A. Ubukata, ¹Y. Yano, ¹T. Tabuchi, ²K. Uchiyama, ²K. Matsumoto

¹Taiyo Nippon Sanso Corporation, Japan

²Taiyo Nippon Sanso EMC Ltd., Japan

P3094B **Evaluation of a Gate-First process for AlGaN/GaN HFETs**

L. Li, T. Shiraishi, A. Kishi, J. Ao, Y. Ohno

The University of Tokushima, Japan